

(12) **United States Patent**
Hamada

(10) **Patent No.:** **US 9,144,975 B2**
(45) **Date of Patent:** **Sep. 29, 2015**

(54) **PIEZOELECTRIC ELEMENT, LIQUID EJECTION HEAD, AND LIQUID EJECTION DEVICE**

2235/449 (2013.01); C04B 2235/768 (2013.01);
C04B 2235/787 (2013.01); C23C 18/1216
(2013.01); H01L 41/318 (2013.01)

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(58) **Field of Classification Search**

None

See application file for complete search history.

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 0 days.

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ABSTRACT

A piezoelectric element having a piezoelectric layer and electrodes. The piezoelectric layer is 3 μm or less in thickness. The piezoelectric layer is made of a piezoelectric material containing a perovskite compound including bismuth manganate ferrate and barium titanate. The piezoelectric layer is preferentially oriented with the (110) plane. A full width at half maximum of the X-ray diffraction peak attributed to the (110) plane is 0.24° or more and 0.28° or less.

4 Claims, 10 Drawing Sheets

(65) **Prior Publication Data**

US 2011/0216133 A1 Sep. 8, 2011

(30) **Foreign Application Priority Data**

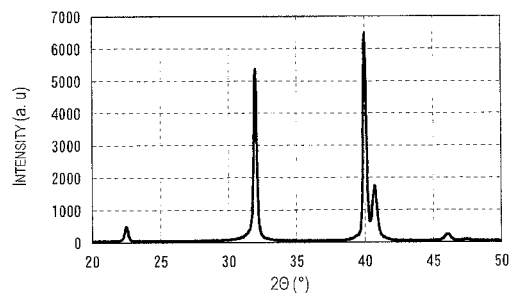
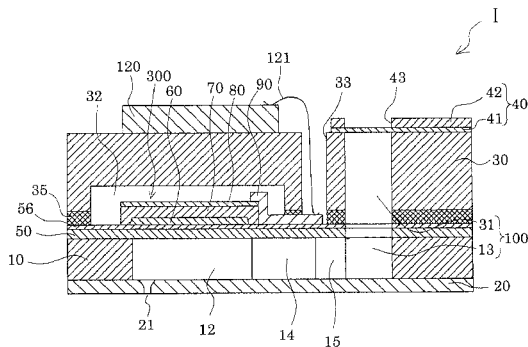
Mar. 2, 2010 (JP) 2010-045973
Jan. 28, 2011 (JP) 2011-015923

(51) **Int. Cl.**

B41J 2/45 (2006.01)
B41J 2/14 (2006.01)
C04B 35/26 (2006.01)
C04B 35/626 (2006.01)
H01L 41/08 (2006.01)
H01L 41/187 (2006.01)
C23C 18/12 (2006.01)
H01L 41/318 (2013.01)

(52) **U.S. Cl.**

CPC **B41J 2/14233** (2013.01); **C04B 35/26** (2013.01); **C04B 35/6264** (2013.01); **H01L 41/0805** (2013.01); **H01L 41/1878** (2013.01); **B41J 2002/14241** (2013.01); **B41J 2002/14419** (2013.01); **B41J 2002/14491** (2013.01); **B41J 2202/03** (2013.01); **C04B 2235/3215** (2013.01); **C04B 2235/3236** (2013.01); **C04B 2235/3262** (2013.01); **C04B 2235/3274** (2013.01); **C04B 2235/3298** (2013.01); **C04B 2235/3418** (2013.01); **C04B 2235/441** (2013.01); **C04B**



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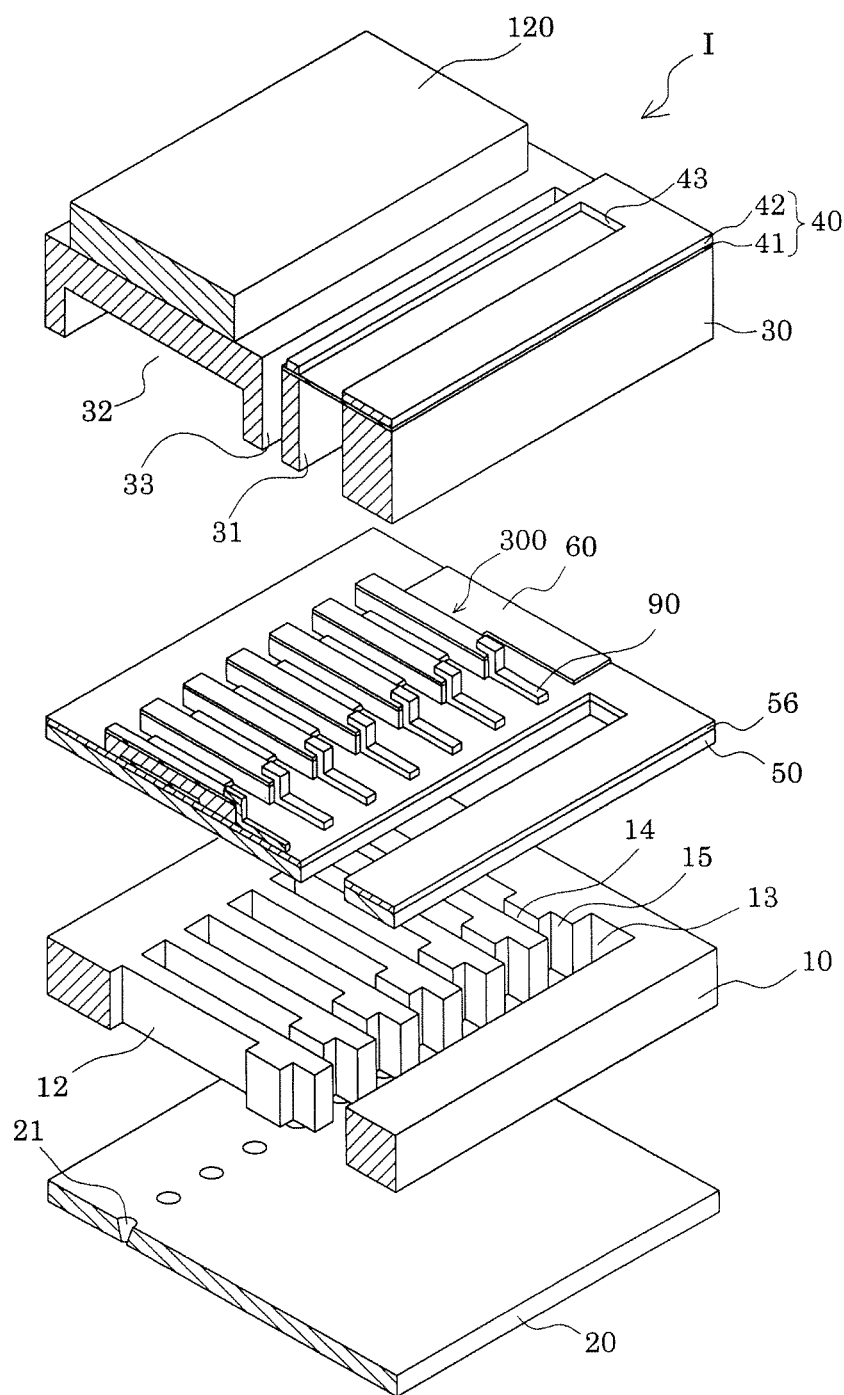
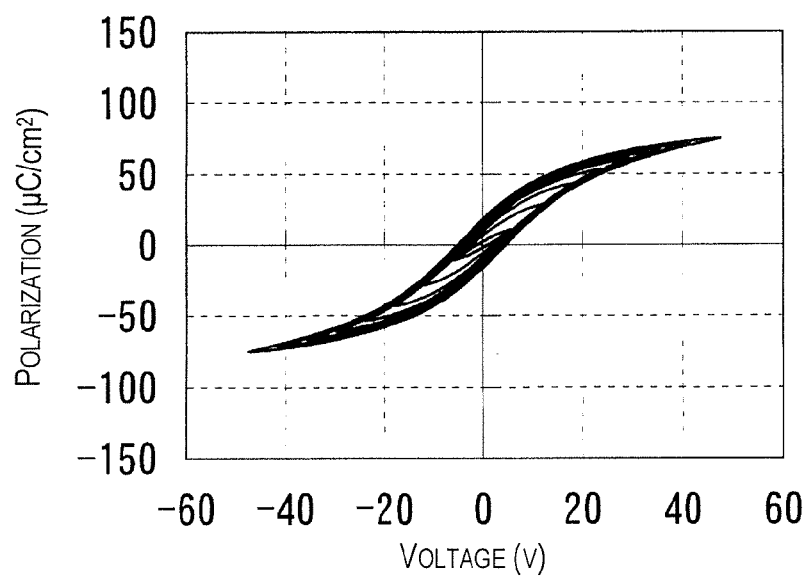
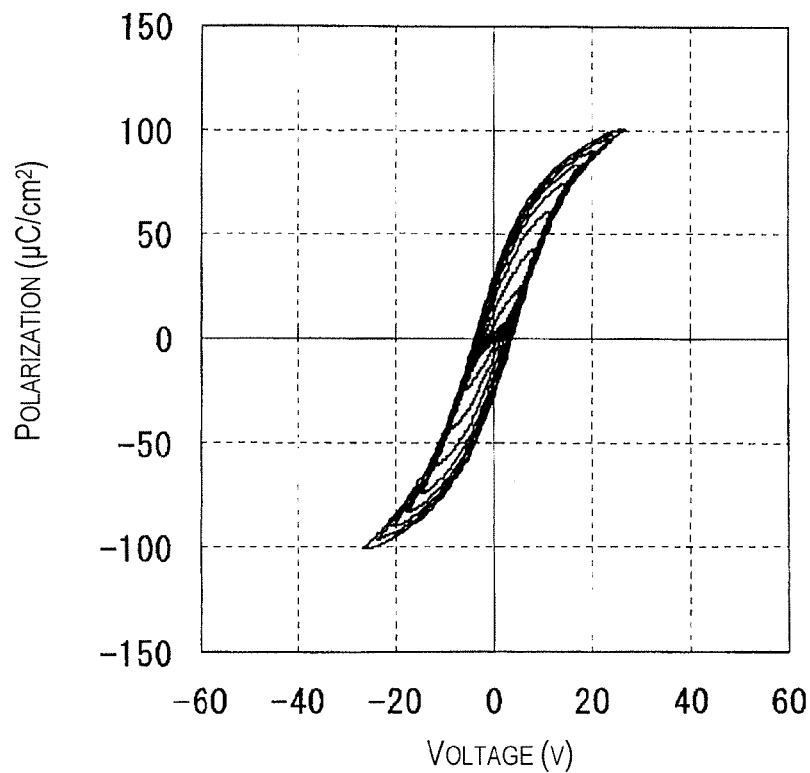
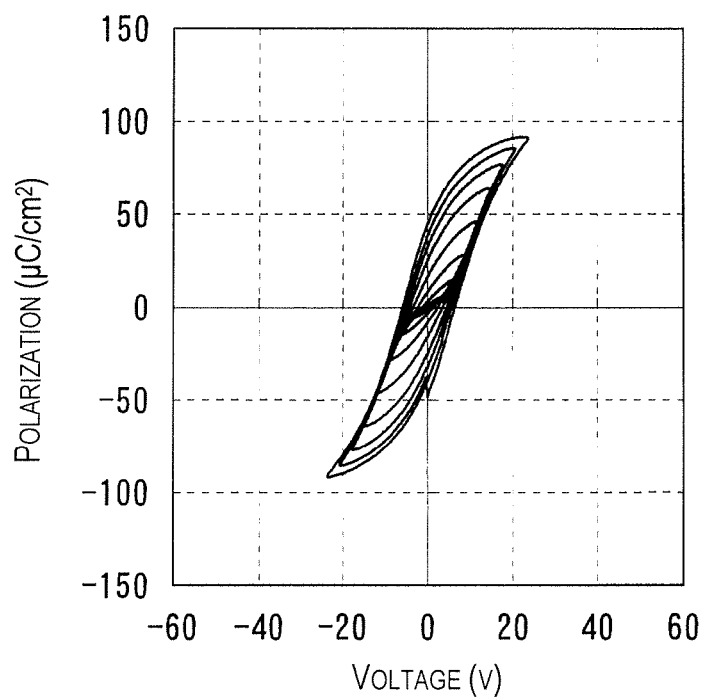
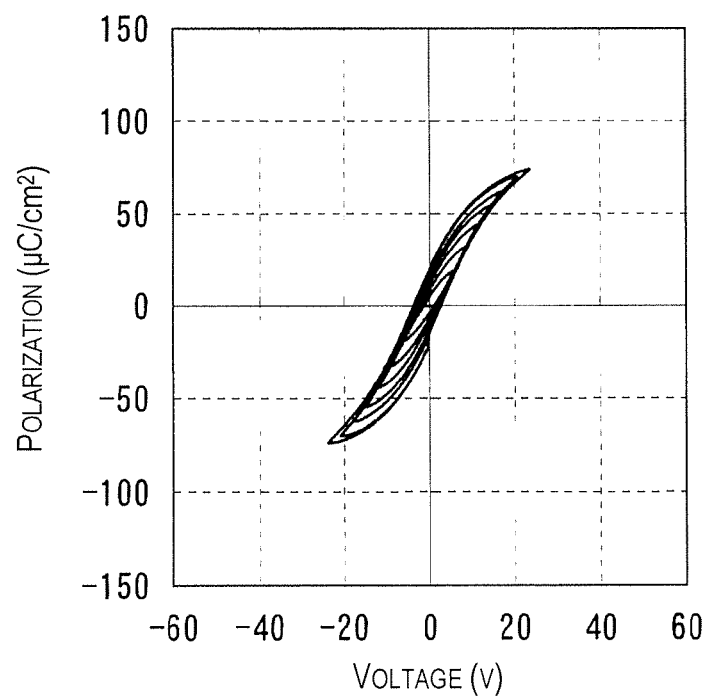
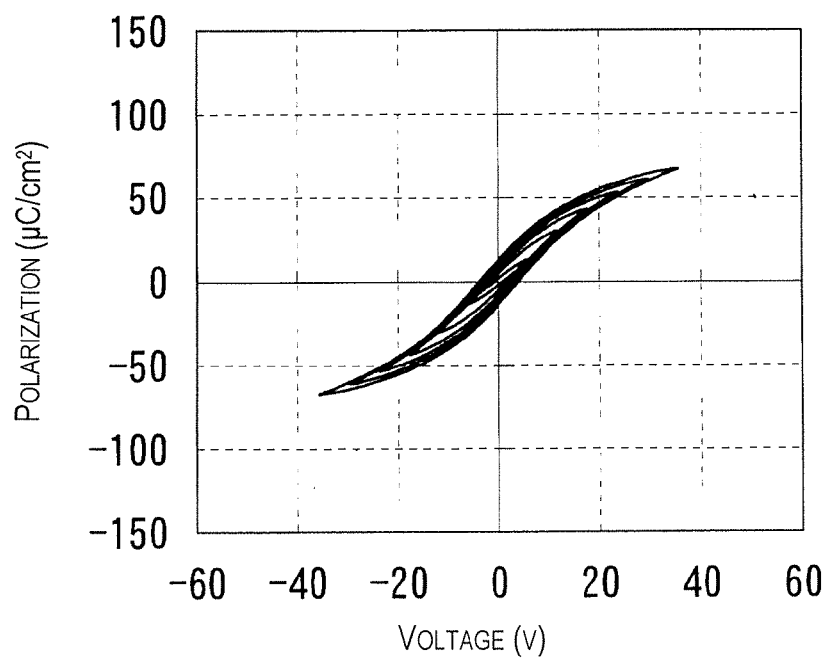
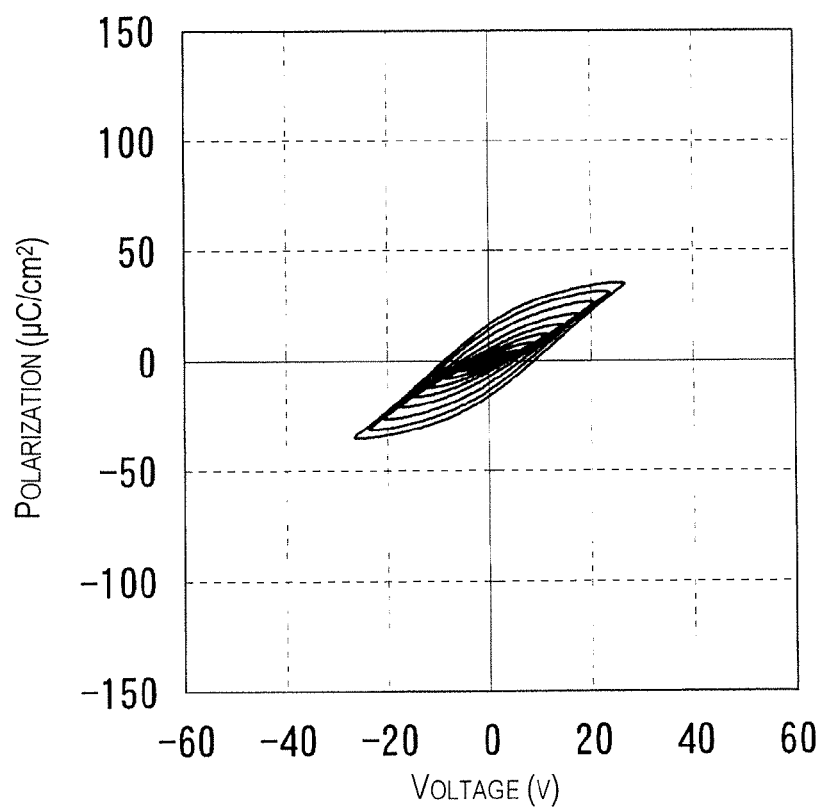


Fig. 1

Fig. 2B

**Fig. 3****Fig. 4**

**Fig. 5****Fig. 6**

**Fig. 7****Fig. 8**

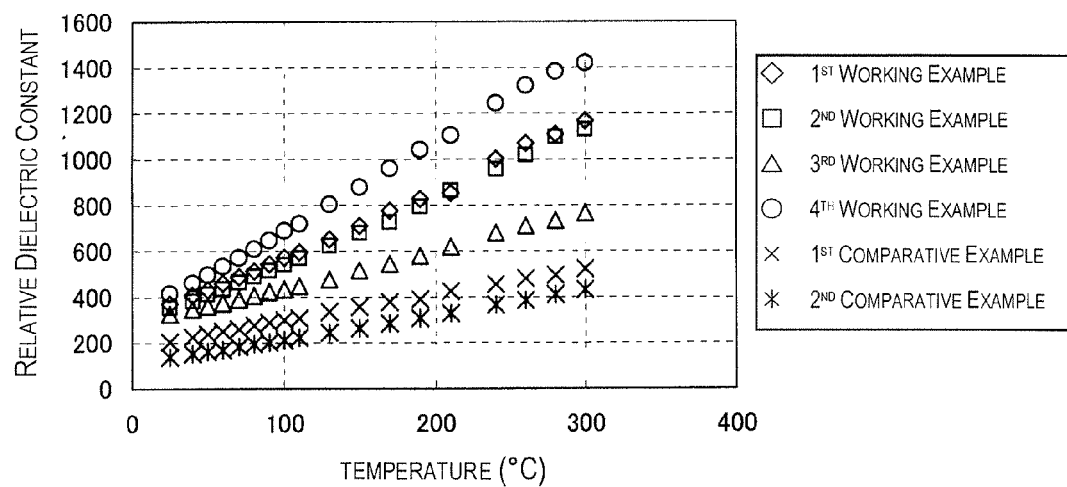


Fig. 9

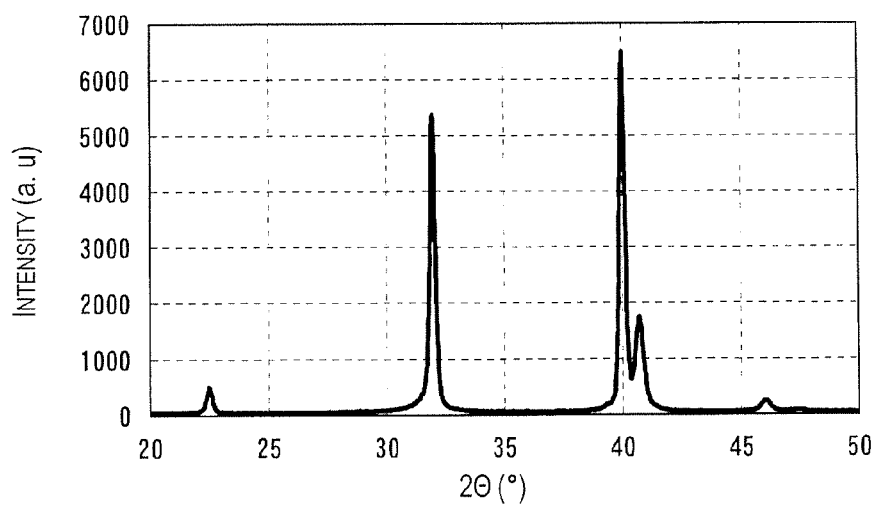
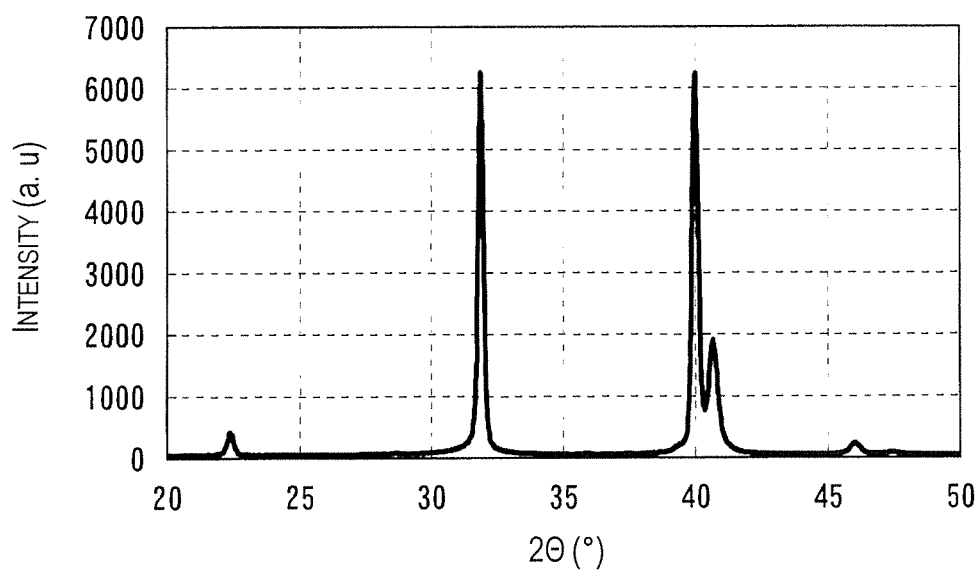
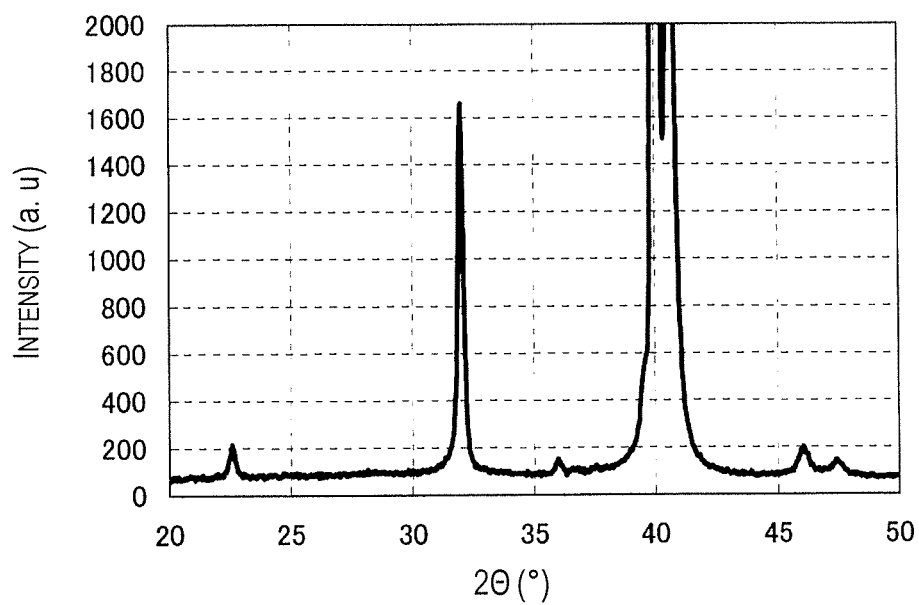
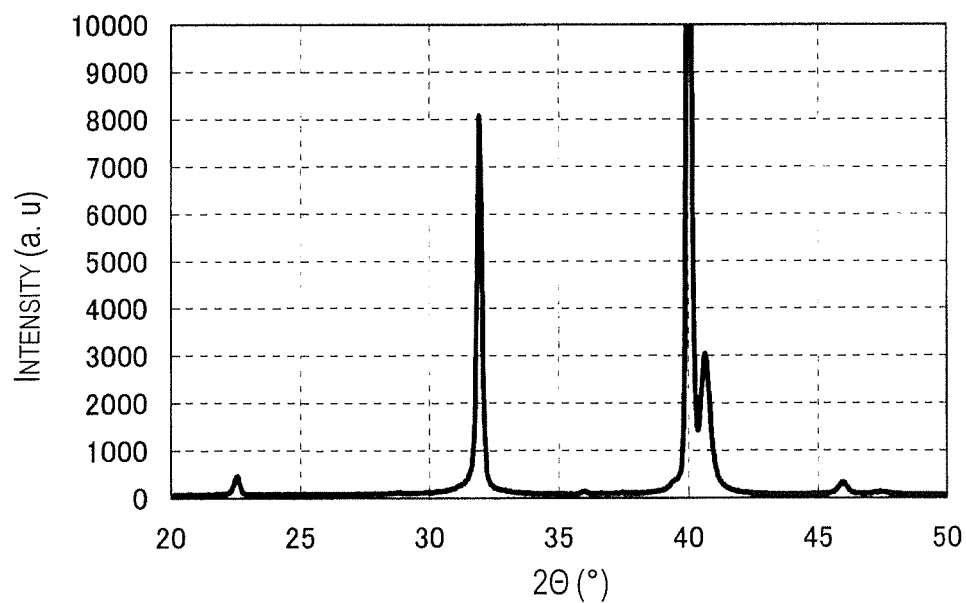
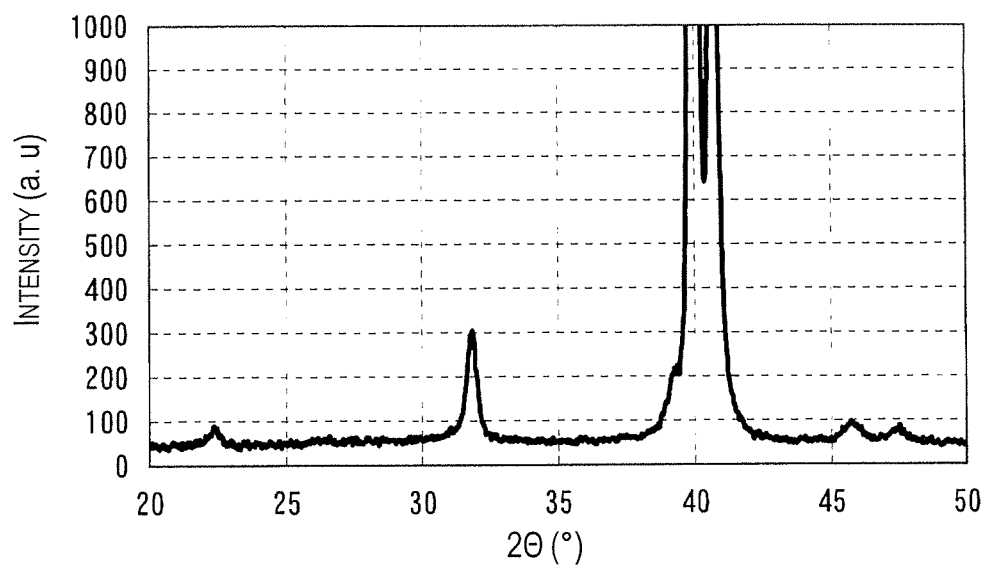


Fig. 10

**Fig. 11****Fig. 12**

**Fig. 13****Fig. 14**

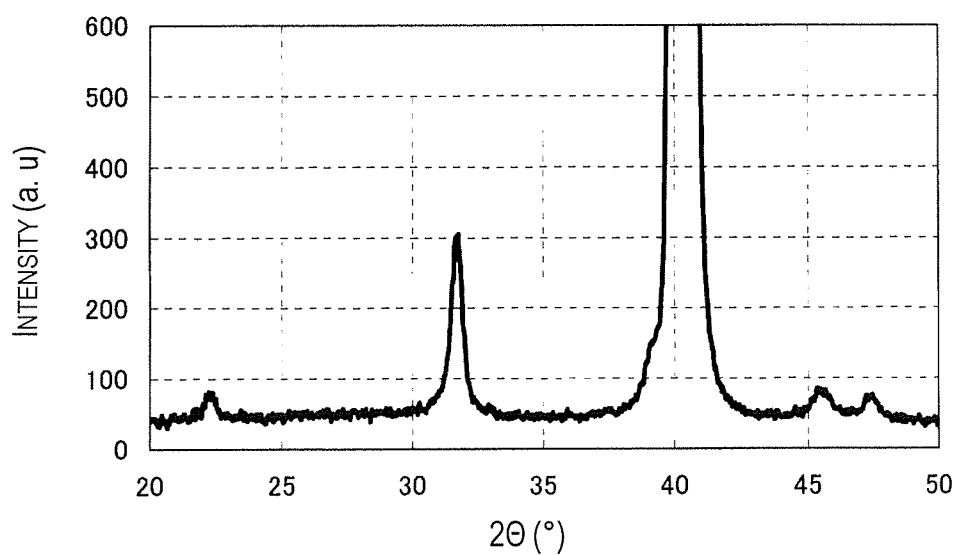


Fig. 15

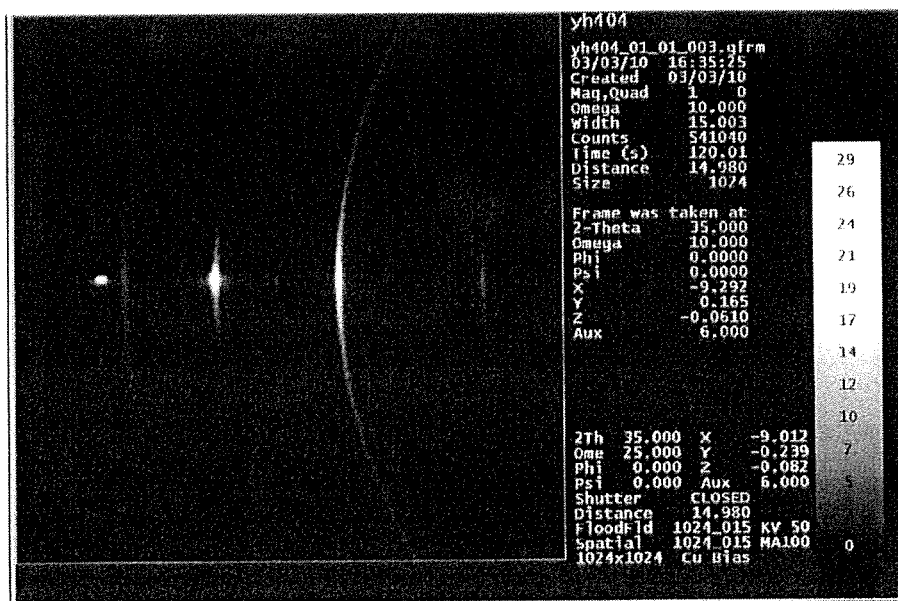


Fig. 16

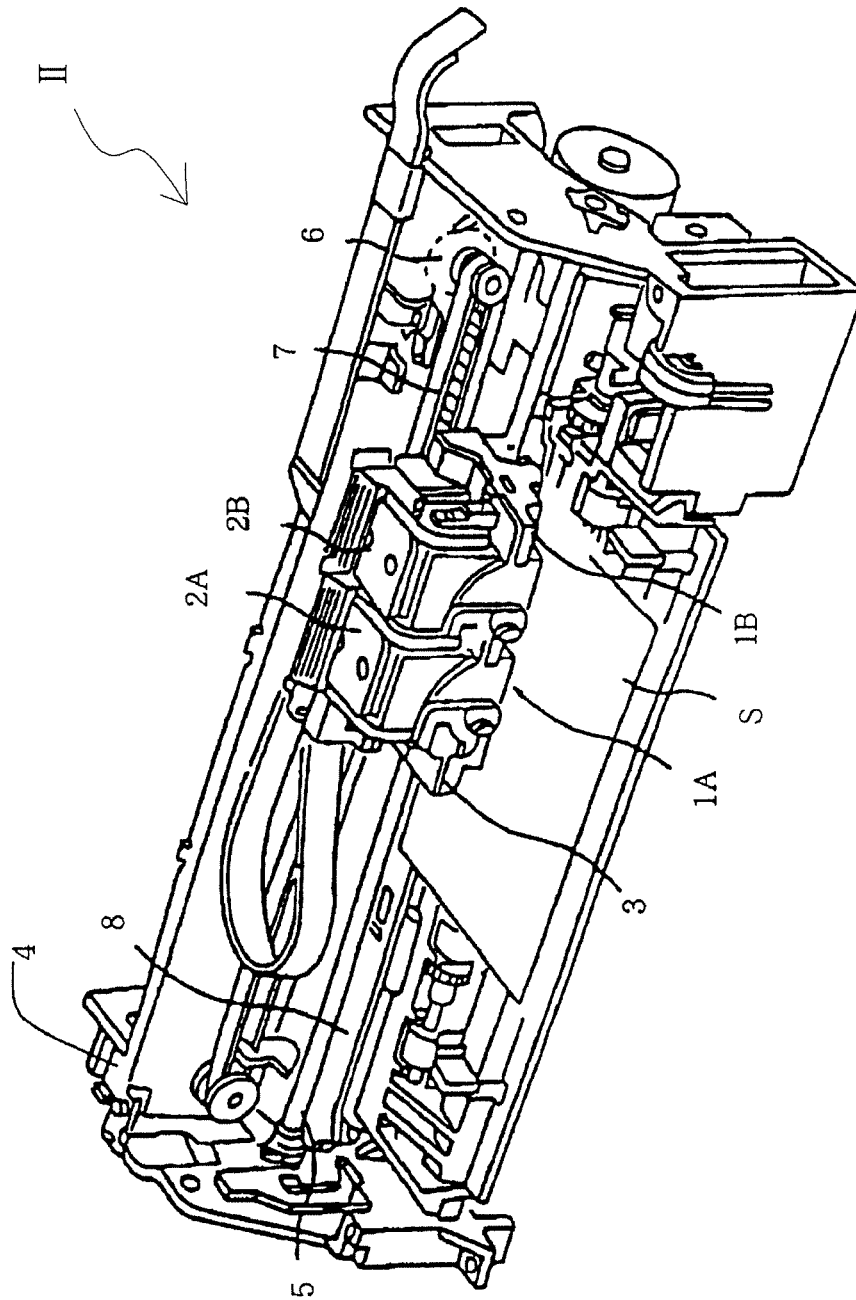


Fig. 17

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PIEZOELECTRIC ELEMENT, LIQUID EJECTION HEAD, AND LIQUID EJECTION DEVICE

CROSS-REFERENCE TO RELATED APPLICATIONS

This application claims priority to Japanese Patent Application No. 2010-045973 filed on Mar. 2, 2010 and Japanese Patent Application No. 2011-015923 filed on Jan. 28, 2011. The entire disclosures of Japanese Patent Application Nos. 2010-045973 and 2011-015923 are hereby incorporated herein by reference.

BACKGROUND

1. Technical Field

The present invention relates to a liquid ejection head and a liquid ejection device provided with piezoelectric elements having electrodes and a piezoelectric layer of a piezoelectric material, and adapted to expel droplets of liquid from nozzle openings.

2. Related Art

One known structure for a piezoelectric element has a piezoelectric layer of a piezoelectric material that exhibits an electrical-mechanical conversion function, for example, a crystallized dielectric material, sandwiched by two electrodes. Piezoelectric elements of this kind may be installed in a liquid ejection head to serve as actuator devices that oscillate in flexural oscillation mode, for example. One typical example of a liquid ejection head, for example, is an inkjet recording head that includes oscillator plates which partially define pressure generation chambers communicating with nozzle openings for expelling ink droplets, the head being adapted to pressurize the ink of the pressure generation chambers through deformation of the oscillator plates by piezoelectric elements in order to expel ink droplets from the nozzle openings. The piezoelectric elements installed in such an inkjet head are produced, for example, by forming a uniform piezoelectric material layer over the entire surface of the oscillator plate by deposition technique, and etching away the piezoelectric material layer by a lithography process into shapes that correspond to the pressure generation chambers, to form an independent piezoelectric element for each of the pressure generation chambers.

An example of a piezoelectric material used in such piezoelectric elements is lead zirconate titanate (PZT) (see Japanese Laid-Open Patent Application Publication No. 2001-223404).

SUMMARY

However, reduced lead levels in piezoelectric materials are increasingly desirable due to environmental concerns. An example of a lead-free piezoelectric material is BiFeO_3 , which has a perovskite structure represented by ABO_3 , for example. A problem with such BiFeO_3 based piezoelectric materials which contain Bi and Fe is that piezoelectric characteristics (strain rate) tend to be low owing to the relatively low relative dielectric constant. This problem is not limited to liquid ejection heads typified by inkjet heads, and similar problems are encountered with piezoelectric elements of actuator devices installed in other types of devices as well.

With the foregoing in view, it is an object of the present invention to provide a liquid ejection head, a liquid ejection device, and a piezoelectric element that are both environmentally friendly and afford a high relative dielectric constant.

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A liquid ejection head according to one aspect of the present invention includes a piezoelectric element having a piezoelectric layer and electrodes provided on the piezoelectric layer. The piezoelectric layer is 3 μm or less in thickness.

5 The piezoelectric layer is made of a piezoelectric material containing a perovskite compound including bismuth manganate ferrate and barium titanate. The piezoelectric layer is preferentially oriented with the (110) plane, with the X-ray diffraction peak attributed to the (110) plane having a full width at half maximum of 0.24° or more and 0.28° or less.

10 According to this aspect, a liquid ejection head having a piezoelectric layer with a low lead content; that is, a reduced lead content, and a high relative dielectric constant is obtained through the use of a piezoelectric layer that is 3 μm or less in thickness, is composed of a piezoelectric material containing a perovskite compound including bismuth manganate ferrate and barium titanate, and is preferentially oriented with the (110) plane, the X-ray diffraction peak attributed to the (110) plane having a full width at half maximum of 0.24° or more and 0.28° or less.

15 The piezoelectric layer preferably further includes SiO_2 . Doing so affords a liquid ejection head having piezoelectric elements with low lead content, a high relative dielectric constant, and excellent insulating properties.

20 The piezoelectric layer preferably contains SiO_2 in an amount of 0.5 mol % or more and 5 mol % or less with respect to the perovskite compound. Doing so affords a liquid ejection head having a piezoelectric layer with dependably low lead content, high relative dielectric constant, and excellent insulating properties.

25 A liquid ejection device according to another aspect of the present invention includes the liquid ejection head of the preceding aspect. According to this aspect, the liquid ejection device is provided with a liquid ejection head having a piezoelectric layer with low lead content and a high relative dielectric constant, thereby affording a device with excellent ejection characteristics and negligible environmental impact.

30 A piezoelectric element according to another aspect of the present invention includes a piezoelectric layer and an electrode provided on the piezoelectric layer. The piezoelectric layer is 3 μm or less in thickness. The piezoelectric layer is made of a piezoelectric material having a perovskite compound including bismuth manganate ferrate and barium titanate. The piezoelectric layer is preferentially oriented with the (110) plane, with the X-ray diffraction peak attributed to the (110) plane having a full width at half maximum of 0.24° or more and 0.28° or less. According to this aspect, a piezoelectric element having a piezoelectric layer with low lead content and a high relative dielectric constant is obtained by using a piezoelectric layer that is 3 μm or less in thickness, is composed of a piezoelectric material containing a perovskite compound including bismuth manganate ferrate and barium titanate, and is preferentially oriented with the (110) plane, with a full width at half maximum of the X-ray diffraction peak being attributed to the (110) plane being 0.24° or more and 0.28° or less.

BRIEF DESCRIPTION OF THE DRAWINGS

60 Referring now to the attached drawings which form a part of this original disclosure:

FIG. 1 is an exploded perspective view of a simplified configuration of a recording head according to a first embodiment.

65 FIG. 2A is a plan view of the recording head, and FIG. 2B is a cross sectional view of the recording head according to the first embodiment.

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FIG. 3 is a drawing depicting a P-V curve in a first embodiment.

FIG. 4 is a drawing depicting a P-V curve in a second embodiment.

FIG. 5 is a drawing depicting a P-V curve in a third embodiment.

FIG. 6 is a drawing depicting a P-V curve in a fourth embodiment.

FIG. 7 is a drawing depicting a P-V curve in a first comparative example.

FIG. 8 is a drawing depicting a P-V curve in a second comparative example.

FIG. 9 is a drawing depicting measurements of relative dielectric constant.

FIG. 10 is a drawing showing an XRD pattern in the first embodiment.

FIG. 11 is a drawing showing an XRD pattern in the second embodiment.

FIG. 12 is a drawing showing an XRD pattern in the third embodiment.

FIG. 13 is a drawing showing an XRD pattern in the fourth embodiment.

FIG. 14 is a drawing showing an XRD pattern in the first comparative example.

FIG. 15 is a drawing showing an XRD pattern in the second comparative example.

FIG. 16 is a 2-dimensional sensed image in the first embodiment.

FIG. 17 is a drawing showing a simplified configuration of a recording device according to an embodiment of the invention.

DETAILED DESCRIPTION OF EXEMPLARY EMBODIMENTS

First Embodiment

FIG. 1 is an exploded perspective view showing a simplified configuration of an inkjet recording head as an example of a liquid ejection head according to a first embodiment of the invention; and FIG. 2A is a plan view and FIG. 2B is a cross sectional view thereof across A-A'.

As shown in FIGS. 1, 2A and 2B, in the present embodiment there is provided a flow-defining substrate 10 made of a single-crystal silicon substrate with a resilient film 50 of silicon dioxide formed on one face.

A plurality of pressure generation chambers 12 are arrayed along the width direction of the flow-defining substrate 10. A communicating portion 13 is formed in a zone situated at the lengthwise outer ends of the pressure generation chambers 12 of the flow-defining substrate 10, and the communicating portion 13 communicates with the pressure generation chambers 12 via ink supply channels 14 and communicating channels 15 which are individually provided to the pressure generation chambers 12. The communicating portion 13 communicates with a reservoir portion 31 of a protective substrate, discussed later, and constitutes part of a reservoir which provides a common ink chamber for the pressure generation chambers 12. The ink supply channels 14 are narrower in width than the pressure generation chambers 12, and serve to maintain a given level of flow channel resistance of the ink inflowing to the pressure generation chambers 12 from the communicating portion 13. In the present embodiment, the ink supply channels 14 are formed by constricting the width of the flow channels from one side; however, the ink supply channels may also be formed by constricting the width of the flow channels from both sides. Alternatively, the ink supply

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channels may be constricted in the thickness direction rather than constricting the width of the flow channels. According to the present embodiment, the flow-defining substrate 10 is provided with liquid flow channels which include the pressure generation chambers 12, the communicating portion 13, the ink supply channels 14, and the communicating channels 15.

A nozzle plate 20 having nozzle openings 21 communicating at locations in proximity to the ends on the opposite side from the ink supply channels 14 in the pressure generation chambers 12 is affixed with an adhesive, thermal welding film, or other means, at the open face of the flow-defining substrate 10. The nozzle plate 20 may be made, for example, of glass-ceramics, a single-crystal silicon substrate, stainless steel, or the like.

Meanwhile, to the opposite side from the open face in this flow-defining substrate 10, the resilient film 50 is formed in the above manner, and over this resilient film 50 there is disposed an intimate adhesion layer 56 of titanium aluminum nitride (TiAlN) or the like intended to improve intimate adhesion of the resilient film 50 to the foundation of a first electrode 60. While TiAlN is used as the intimate adhesion layer 56 in the present embodiment, the material of the intimate adhesion layer 56 may differ depending on factors such as the type of first electrode 60 and the foundation for it; oxides or nitrides containing titanium, zirconium, or aluminum, or SiO₂, MgO, CeO₂, or the like may be used. Optionally, an insulator film of zirconium oxide or the like may be formed between the resilient layer and the intimate adhesion layer 56.

The first electrode 60, a piezoelectric layer 70 which is a thin film 3 μm or less, preferably between 0.3 and 1.5 μm, in thickness and preferentially oriented with the (110) plane (for example, 60% or more), and a second electrode 80, are built up over the intimate adhesion layer 56 to form a piezoelectric element 300. Here, the piezoelectric element 300 refers to the section that includes the first electrode 60, the piezoelectric layer 70, and the second electrode 80. Typically, either one of the electrodes of the piezoelectric element 300 is provided as a common electrode, while the other electrode and the piezoelectric layer 70 are patterned individually for each of the pressure generation chambers 12. In the present embodiment, the first electrode 60 is provided as the common electrode for the piezoelectric elements 300, while the second electrode 80 is an individual electrode provided to each of the piezoelectric elements 300; however, reversing this arrangement due to driver circuit or wiring considerations poses no particular difficulty. Here, the piezoelectric element 300 and the oscillator plate that gives rise to displacement driven by the piezoelectric element 300 are together termed an actuator unit. In the example described above, the resilient film 50, the intimate adhesion layer 56, and the first electrode 60, and the optional insulator film act as the oscillator plate; however, no limitation thereto is imposed, and the resilient film 50 and the intimate adhesion layer 56 need not be provided, for example. Alternatively, the piezoelectric element 300 may substantially double as the oscillator plate.

In the present embodiment, the piezoelectric layer 70 is made from a piezoelectric material containing a perovskite compound that includes bismuth manganate ferrate and barium titanate. A perovskite compound is a compound having the perovskite structure. This perovskite structure specifically produces an 8-faced body (octagon) of ABO₃ structure in which the A site has 12-fold oxygen coordination and the B site has 6-fold oxygen coordination. Bi or Ba are situated at the A sites, while Fe, Mn, or Ti is situated at the B sites.

As mentioned above, the piezoelectric layer 70 is preferentially oriented with the (110) plane, and the X-ray diffrac-

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tion peak attributed to this (110) plane has a full width at half maximum of 0.24° or more and 0.28° or less. When the piezoelectric layer **70** is measured using wide angle X-ray diffraction (XRD), diffraction intensity peaks equivalent to the (100) plane, the (110) plane, and the (111) plane are observed. "Full width at half maximum" (FWHM) refers to width observed at half of peak intensity corresponding to the crystal planes in the X-ray diffraction chart (the difference between diffraction angles at two points having a value equal to half the maximum value of a peak).

Where the piezoelectric layer **70** is $3\text{ }\mu\text{m}$ or less in thickness, is made of a perovskite compound that includes bismuth manganate ferrate and barium titanate, and is preferentially oriented with the (110) plane with the X-ray diffraction peak attributed to this (110) plane having a full width at half maximum of 0.24° or more and 0.28° or less, the piezoelectric layer **70** of the resultant piezoelectric element **300** will be lead-free yet have a high relative dielectric constant, as shown in the embodiments discussed later. Consequently, the piezoelectric layer **70** will have good piezoelectric characteristics such that, for example, the oscillator plate experiences large displacement at small voltages.

In preferred practice the piezoelectric layer **70** further contains SiO_2 . It is hypothesized that this SiO_2 does not substitute onto the A sites or B sites in the perovskite compound, but rather is present as SiO_2 at grain boundaries of the perovskite compound formed, for example, by the bismuth manganate ferrate and the barium titanate (e.g., $(\text{Bi}, \text{Ba})(\text{Fe}, \text{Mn}, \text{Ti})\text{O}_3$). By including SiO_2 in the piezoelectric layer **70**, the resultant piezoelectric element **300** will be lead-free and will have a high relative dielectric constant and excellent insulating properties, as shown in the embodiments discussed later. It is hypothesized that the reason for the excellent insulating properties is that the presence of SiO_2 at grain boundaries in the perovskite compound has the effect of inhibiting leak paths.

The perovskite compound contained in the piezoelectric layer **70** may contain other compounds having the perovskite structure, for example, $\text{BiZn}_{1/2}\text{Ti}_{1/2}\text{O}_3$, $(\text{Bi}_{1/2}\text{K}_{1/2})\text{TiO}_3$, $(\text{Bi}_{1/2}\text{Na}_{1/2})\text{TiO}_3$, or $(\text{Li}, \text{Na}, \text{K})(\text{Ta}, \text{Nb})\text{O}_3$.

No particular limitation is imposed as to the ratio of Fe and Mn of the bismuth manganate ferrate which is a principal component of the perovskite compound, and the level of Mn may be more than 1 mol % but less than 10 mol % of the total molar quantity of Fe and Mn. Nor is any particular limitation imposed as to the proportions of bismuth manganate ferrate, barium titanate, or the optional SiO_2 . For example, the level of bismuth manganate ferrate is more than 60 mol %, and preferably at least 70 mol % but not more than 80 mol %, with respect to the perovskite compound, more specifically to the total molar quantity of bismuth manganate ferrate, barium titanate, etc. Consequently, the proportion of compounds having the perovskite structure such as barium titanate is less than 40 mol % in the perovskite compound. Such a perovskite compound composed, for example, of bismuth manganate ferrate and barium titanate is represented by Equation (1) below.



($0.60 < x < 1$, $0 < y < 0.40$, and preferably $0.70 \leq x \leq 0.80$, $0.20 \leq y \leq 0.30$, $x+y=1$, and $0.01 < a < 0.10$.)

While no particular limitation is imposed as to the level of SiO_2 where included in the piezoelectric layer **70**, the piezoelectric layer **70** may be made of piezoelectric material containing at least 0.5 mol % but no more than 5 mol %, preferably at least 1.5 mol % but no more than 2.5 mol %, with respect to the perovskite compound.

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No particular limitation is imposed as to the method of forming such piezoelectric elements **300** on the flow-defining substrate **10**, and the elements may be manufactured by the following method, for example. First, a silicon dioxide film of silicon dioxide (SiO_2) or the like constituting the resilient film **50** is formed on the surface of the wafer that used for the flow-defining substrate, which is a silicon wafer. Next, the intimate adhesion layer **56** of titanium aluminum nitride or the like is formed over the resilient film **50** (silicon dioxide film).

Next, the first electrode **60** composed of platinum, iridium, iridium oxide, or a stacked layer structure thereof is formed over the entire face of the intimate adhesion layer **56** by a sputtering process or the like, and then patterned.

Next, the piezoelectric layer **70** is built up. No particular limitation is imposed as to the method of manufacture of the piezoelectric layer **70**, but the piezoelectric layer **70** may be formed, for example, using a metal-organic decomposition (MOD) method involving dissolving/dispersing a metal compound in a solvent then applying and drying the solution, followed by baking at high temperature to obtain a piezoelectric layer **70** made of metal oxide. The method of manufacture of the piezoelectric layer **70** is not limited to MOD, and other methods, for example, chemical solution methods such as the sol-gel method, laser ablation methods, sputtering methods, pulsed laser deposition (PLD) methods, CVD methods, aerosol deposition methods, and the like may be used as well.

For example, a sol or MOD solution (precursor solution) that contains a desired composition ratio of metal compounds, specifically, metal compounds including Bi, Fe, Mn, Ba, and Ti, and that optionally contains added SiO_2 , is applied onto the first electrode **60** by a spin coating method, etc., to form a piezoelectric precursor film (coating step).

The coated precursor solution is prepared by combining metal compounds that respectively include Bi, Fe, Mn, Ba, and Ti so as to give the desired molar ratios of each metal, and dissolving or dispersing the mixture into an organic solvent such as an alcohol. As metal compounds respectively including Bi, Fe, Mn, Ba, and Ti there may be employed, for example, metal alkoxides, salts of organic acids, β diketone complexes, and the like. Examples of metal compounds containing Bi include bismuth benzoate, bismuth oxyacetate, bismuth octylate, bismuth octanoate, bismuth citrate, bismuth acetate, tri-*n*-amylbismuth, triethoxy bismuth, tris(dipivaloylmethanate) bismuth, triphenyl bismuth, and tri-*i*-propoxy bismuth. Examples of metal compounds containing Fe include iron octylate, iron octanoate, iron formate, iron stearate, triethoxy iron, iron tris(acetylacetonate), tri-*i*-propoxy iron, and the like. Examples of metal compounds containing Mn include manganese octylate, manganese octanoate, manganese acetate, manganese acetylacetonate, and the like. Examples of metal compounds containing Ba include barium benzoate, barium octanoate, barium octylate, barium oleate, barium formate, barium citrate, barium acetate, barium oxalate, barium tartrate, diethoxy barium, di-*i*-butoxy barium, di-*n*-butoxy barium, di-sec-butoxy barium, di-*t*-butoxy barium, di-*i*-propoxy barium, di-*n*-propoxy barium, dimethoxy barium, barium hydroxide, barium thiocyanate, barium naphthenate, barium lactate, barium dipivaloylmethanate, barium di(methoxyethoxide), bis(acetylacetonate)diaqua barium, bis(dipivaloylmethanate) barium, barium propionate, and barium laurate. Examples of metal compounds containing Ti include titanium octylate, titanium octanoate, titanium oleate, di(isopropoxy) bis(dipivaloylmethanate) titanium, tetraethoxy titanium, tetrakisdiethylamino titanium, tetrakis(dimethylamino) titanium, tetra-*n*-butoxy titanium, tetra-*i*-butoxy titanium, tetra-sec-bu-

toxy titanium, tetra-t-butoxy titanium, tetra-i-propoxytitanium, tetra-n-propoxy titanium, tetramethoxy titanium, and the like. Solvents for the precursor solution include propanol, butanol, pentanol, hexanol, octanol, ethylene glycol, propylene glycol, octane, decane, cyclohexane, xylene, toluene, tetrahydrofuran, acetic acid, octylic acid, and the like.

In preferred practice, the precursor solution is one that includes iron octylate. Where iron octylate is included, simply by forming a piezoelectric precursor film by coating or the like and bringing about crystallization thereof by heating, a piezoelectric layer **70** that is preferentially oriented with the (110) plane can be formed through spontaneous orientation, that is, without an operation to orient the material under an applied magnetic field, or an operation involving providing the foundation of the piezoelectric layer **70** with a layer for controlling orientation, or the like. The precursor solution including iron octylate may be a precursor solution containing added iron octylate per se as the iron source, or one in which a metal compound other than iron octylate is used as the iron source, and a precursor solution for coating purposes that contains iron octylate is obtained through ligand substitution by the solvent or the like. In case of a precursor solution that does not include iron octylate, for example, one including iron tris(acetylacetonate), coating of the precursor solution and bringing about crystallization of the piezoelectric precursor film by heating does not bring about a piezoelectric layer **70** that is preferentially oriented with the (110) plane.

Next, the piezoelectric precursor film is heated to prescribed temperature and dried for a given duration (drying step). Next, the dried piezoelectric precursor film is heated to a prescribed temperature and held for a given duration to bring about degreasing (degreasing step). Here, degreasing refers to driving off organic components contained in the piezoelectric precursor film, for example, NO_2 , CO_2 , H_2O , and so on.

Next, the piezoelectric precursor film is heated to prescribed temperature, for example between 600°C . and 700°C ., and held for a given duration to bring about crystallization and form the piezoelectric film (baking step). The heating unit used in the drying step, degreasing step, and baking step may be a rapid thermal annealing (RTA) unit designed to heat by irradiation with a UV lamp, or a hot plate or other device.

Optionally, the aforementioned coating step, drying step, and degreasing step or the coating step, drying step, degreasing step, and baking step may be repeated multiple times depending on factors such as desired film thickness, to form a piezoelectric layer composed of a multilayer piezoelectric film.

During formation of the piezoelectric layer **70**, the full width at half maximum value of the X-ray diffraction peak attributed to the (110) plane may be adjusted by varying the elemental ratios of Bi, Fe, Mn, Ba and Ti of the precursor solution.

Also, the extent of orientation of the (110) plane of the piezoelectric layer **70** may be adjusted by varying the elemental ratios of Bi, Fe, Mn, Ba and Ti of the precursor solution or through adjustment of the ligands of the elements by varying the solvent or metal compounds.

After the piezoelectric layer **70** has been formed, the second electrode **80** layer is formed from a metal such as platinum, for example, over the piezoelectric layer **70**; and the piezoelectric layer **70** and the second electrode **80** are then patterned simultaneously to form the piezoelectric element **300**.

Optionally, a subsequent post-anneal may be carried out at a temperature range of between 600°C . and 700°C . By so doing, a good interface can be formed between the piezoelec-

tric layer **70** on the one hand and the first electrode **60** and second electrode **80** on the other, and the crystallinity of the piezoelectric layer **70** may be improved.

A more detailed description of the present invention is given below based on the preferred working examples. The invention is not limited to the working examples hereinbelow.

First Working Example

First, an SiO_2 film having film thickness of 400 nm was formed by thermal oxidation of the surface of a silicon substrate. Next, using an RF sputtering method, a TiAlN film having film thickness of 100 nm was formed over the SiO_2 film. Next, using a DC sputtering method, an Ir film having film thickness of 100 nm and an IrO_2 film having film thickness of 30 nm were formed successively over the TiAlN film, and a Pt film oriented in the (111) plane was formed thereon by a vapor deposition method, to form the first electrode **60**.

Next, a piezoelectric layer was formed on the first electrode by a spin coating method. The method is as follows. First, metal compounds of Bi, Fe, Mn, Ba, Ti, and Si, more specifically bismuth octylate, iron octylate, manganese octylate, barium octylate, titanium octylate, and SiO_2 , together with an octane solvent, are mixed in prescribed proportions to prepare a precursor solution. In the resultant solution the total number of moles of Bi, Fe, Mn, Ba, and Ti was 0.25 mol/L. This precursor solution was dripped onto the substrate on which the TiAlN film and the first electrode were formed, and the substrate was then spun at 1,500 rpm to form a piezoelectric precursor film (coating step). Next, drying/degreasing were carried out for 3 minutes at 350°C . (drying and degreasing step). After repeating this coating step and drying and degreasing step three times, baking was carried by rapid thermal annealing (RTA) for one minute at 650°C . (baking step). After repeating four times a process of carrying out the coating step and drying and degreasing step three times followed by a baking step of baking the entire layer, baking was carried out by RTA for 10 minutes at 650°C . to form a piezoelectric layer **70** having total thickness of 800 nm by a total of 12 successive coatings.

Subsequently, after forming a platinum film 100 nm in thickness as the second electrode **80** on the piezoelectric layer **70** by a DC sputtering method, baking was carried out by RTA for 10 minutes at 650°C . to form a piezoelectric element **300** of a piezoelectric layer **70** of piezoelectric material containing a perovskite compound having the compositional ratio $0.75\text{ Bi}(\text{Fe}_{0.95}\text{Mn}_{0.05})\text{O}_3$ - 0.25 BaTiO_3 , and 2 mol % SiO_2 with respect to the perovskite compound.

Second Working Example

A piezoelectric element **300** was formed analogously to the first working example, except that the Si compound was not added to the precursor solution, and the piezoelectric material of the piezoelectric layer **70** was composed of the perovskite compound $0.75\text{ Bi}(\text{Fe}_{0.95}\text{Mn}_{0.05})\text{O}_3$ - 0.25 BaTiO_3 .

Third Working Example

A piezoelectric element **300** was formed analogously to the second working example, except that the mixture proportions of the Bi, Fe, Mn, Ba, and Ti metal compounds were changed to give a piezoelectric layer **70** of a piezoelectric material composed of the perovskite compound $0.80\text{ Bi}(\text{Fe}_{0.95}\text{Mn}_{0.05})\text{O}_3$ - 0.20 BaTiO_3 .

Fourth Working Example

A piezoelectric element **300** was formed analogously to the second working example, except that the mixture proportions

of the Bi, Fe, Mn, Ba, and Ti metal compounds were changed to give a piezoelectric layer **70** of a piezoelectric material of composed of the perovskite compound $0.70 \text{ Bi}(\text{Fe}_{0.95}\text{Mn}_{0.05})\text{O}_3$ - 0.30 BaTiO_3 .

First Comparative Example

A piezoelectric element **300** was formed analogously to the first working example, except that the mixture proportions of the Bi, Fe, Mn, Ba, Ti, and Si metal compounds were changed to give a piezoelectric layer **70** composed of a piezoelectric material having the perovskite compound $0.60 \text{ Bi}(\text{Fe}_{0.95}\text{Mn}_{0.05})\text{O}_3$ - 0.40 BaTiO_3 , and 2 mol % SiO_2 with respect to the perovskite compound.

Second Comparative Example

A piezoelectric element **300** was formed analogously to the first comparative example, except that the Si compound was not added to the precursor solution, and the piezoelectric material of the piezoelectric layer **70** was composed of the perovskite compound $0.60 \text{ Bi}(\text{Fe}_{0.95}\text{Mn}_{0.05})\text{O}_3$ - 0.40 BaTiO_3 .

First Test Example

For each of the piezoelectric elements **300** of the first to fourth working examples and the first and second comparative examples, using an FCE-1A made by Toyo Corporation and a $\phi=400 \mu\text{m}$ electrode pattern, a 3 V to 60 V triangular wave having frequency of 1 kHz was applied and the P (polarization)-V (voltage) relationship was calculated. The hysteresis loop of the first working example is shown in FIG. 3, the hysteresis loop of the second working example is shown in FIG. 4, the hysteresis loop of the third working example is shown in FIG. 5, the hysteresis loop of the fourth working example is shown in FIG. 6, the hysteresis loop of the first comparative example is shown in FIG. 7, and the hysteresis loop of the second comparative example is shown in FIG. 8. As shown in FIGS. 3 to 8, the piezoelectric layers of the first to fourth working examples and of the first and second comparative examples are ferroelectrics.

As a result, polarization was greater in the first to fourth working examples as compared with the first and second comparative examples. In the first working example, a good hysteresis curve was obtained up to 51 V. It was therefore demonstrated that the first working example affords excellent insulation properties.

Second Test Example

For each of the piezoelectric elements **300** of the first to fourth working examples and the first and second comparative examples, using an impedance analyzer HP4294A made by Agilent, relative dielectric constant ϵ_r was measured at between 25°C . and 300°C . under conditions of 1 kHz and 141 mV amplitude. Results are shown in FIG. 9. As shown in FIG. 9, the piezoelectric layer **70** in the first to fourth working examples had markedly higher relative dielectric constant ϵ_r , as compared with the first and second comparative examples, and relative dielectric constant ϵ_r was **320** or above. Specifically, as shown in FIG. 9, relative dielectric constant at 25°C . was **370** for the first working example, **355** for the second working example, **325** for the third working example, and **415** for the fourth working example, versus **205** for the first comparative example and **140** for the second comparative example.

Third Test Example

For each of the piezoelectric elements of the first to fourth working examples and the first and second comparative examples, using a D8 Discover made by Bruker AXS and $\text{CuK}\alpha$ rays as the X-ray source, the powder X-ray diffraction patterns of the piezoelectric layers at room temperature were calculated at $\phi=\psi=0^\circ$. Results for the first working example are shown in FIG. 10, results for the second working example in FIG. 11, results for the third working example in FIG. 12, results for the fourth working example in FIG. 13, results for the first comparative example in FIG. 14, and results for the second comparative example in FIG. 15. An example of a 2-dimensional sensed image for the first working example is shown in FIG. 16.

As a result, in all of the first to fourth working examples and the first and second comparative examples, the perovskite structure (ABO_3 structure) was observed to form as shown in FIGS. 10 to 15. The peaks attributed to the piezoelectric layer were one attributed to the (100) plane, observed in proximity to $2\theta=22.30$ to 22.60° , and one attributed to the (110) plane, observed in proximity to $2\theta=31.80$ to 32.00° . When the degree of orientation of the peak attributed to the (110) plane was calculated from the area ratio of the peak attributed to the (110) plane to the sum of the peak attributed to the (100) plane and the peak attributed to the (110) plane, the value was 64% in the first working example, 77% in the second working example, 68% in the third working example and 73% in the fourth working example. Thus, these values were 60% or above for the first to fourth working examples, showing that all of the oriented films were preferentially oriented with the (110) plane. The peak attributed to the (111) plane observed in proximity to $2\theta=40^\circ$ is attributed not to the piezoelectric layer but instead to the platinum film of the foundation, and by observing the 2-dimensional sensed image of FIG. 16 in the ψ - 2θ direction, it may be appreciated that the (111) plane peak of the piezoelectric layer of the first working example is extremely small. Moreover, the full width at half maximum of the peak attributed to the (110) plane observed in proximity to $2\theta=31.80$ to 32.00° in the first working example was 0.28° as shown in FIG. 10, that in the second working example was 0.24° as shown in FIG. 11, that in the third working example was 0.26° as shown in FIG. 12, that in the fourth working example was 0.24° as shown in FIG. 13, that in the first comparative example was 0.44° as shown in FIG. 14, and that in the second comparative example was 0.52° as shown in FIG. 15.

From the results of these test examples, it may be appreciated that the first to fourth working examples in which the full width at half maximum of the peak attributed to the (110) plane lies within a range of 0.24° or more and 0.28° or less, the relative dielectric constant is markedly higher and the piezoelectric characteristics are better, as compared with the first and second comparative examples which lie outside the range of 0.24° or more and 0.28° or less.

To the second electrodes **80** provided as the individual electrodes of the piezoelectric element **300** there are connected lead electrodes **90** of gold (Au) for example, which lead out from the proximity of the end on the ink supply channel **14** side and extend as far as the intimate adhesion layer **56**.

A protective substrate **30** having a reservoir portion **31** that defines at least part of a reservoir **100** is joined through the agency of an adhesive **35** over the flow-defining substrate **10** having these piezoelectric elements **300** formed thereon, and more specifically over the first electrode **60**, the intimate adhesion layer **56**, and the lead electrodes **90**. According to

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the present working example, this reservoir portion **31** passes through the protective substrate **30** in the thickness direction and extends across the width direction of the pressure generation chambers **12** to constitute the reservoir **100** which communicates with the communicating portion **13** of the flow-defining substrate **10**, and serves as the common ink chamber for the pressure generation chambers **12** as described previously. Optionally, the communicating portion **13** of the flow-defining substrate **10** may be divided into multiple partitions for the individual pressure generation chambers **12**, and only the reservoir portion **31** used as the reservoir. Alternatively, for example, the flow-defining substrate **10** may be provided with pressure generation chambers **12** only, and a component interposed between the flow-defining substrate **10** and the protective substrate **30** (for example, the resilient film **50**, the intimate adhesion layer **56**, etc.) may be provided with the ink supply channels **14** for connecting the reservoir with the pressure generation chambers **12**.

An area of the protective substrate **30** facing towards the piezoelectric elements **300** is provided with a piezoelectric element retaining portion **32** having space sufficient to not impede movement of the piezoelectric elements **300**. While the piezoelectric element retaining portion **32** must have space sufficient to not impede movement of the piezoelectric elements **300**, the space may be sealed, or not sealed.

The protective substrate **30** is preferably made of material with a coefficient of thermal expansion substantially identical to the flow-defining substrate **10**, for example, glass, ceramic materials, or the like. In the present working example, a single-crystal silicon substrate of material substantially identical to the flow-defining substrate **10** is used.

A passage hole **33** that passes through the protective substrate **30** in the thickness direction is provided in the protective substrate **30**. The lead electrodes **90** which lead out from the piezoelectric elements **300** are disposed such that an area in proximity to the ends of the electrodes lies exposed within the passage hole **33**.

A driver circuit **120** for driving the array of piezoelectric elements **300** is fastened over the protective substrate **30**. A circuit board, a semiconductor integrated circuit (IC), or the like may be used as this driver circuit **120**. The driver circuit **120** and the lead electrodes **90** are electrically connected via connecting lines **121** of conductive wires such as bonding wires.

A compliance substrate **40** composed of a sealing film **41** and a fastener plate **42** is joined onto the protective substrate **30**. Here, the sealing film **41** is made of a pliable material with low rigidity, and one face of the reservoir portion **31** is sealed by this sealing film **41**. The fastener plate **42** is made of relatively hard material. An area of the fastener plate **42** facing the reservoir **100** constitutes an opening portion **43** where material has been completely removed in the thickness direction, and therefore the one face of the reservoir **100** is sealed by the pliable sealing film **41** exclusively.

According to the inkjet recording head I of the present working example, ink is drawn in through an ink introduction port that is connected to external ink supply means, not shown; and after the interior has filled with ink from the reservoir **100** to the nozzle openings **21**, in accordance with a recording signal from the driver circuit **120**, voltage is applied across the first electrodes **60** and the second electrodes **80** respectively corresponding to the pressure generation chambers **12**, to induce the resilient film **50**, the intimate adhesion layer **56**, the first electrode **60**, and the piezoelectric layer **70** to experience flexural deformation and thereby elevate the pressure inside the pressure generation chambers **12** and expel ink droplets.

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Additional Embodiments

While the present invention has been described in terms of certain preferred working examples, the basic configuration of the invention is not limited to those discussed above. For example, piezoelectric layers may be made from piezoelectric materials that additionally contain Ni, Co, Cr, Sc, V or the like, for the purpose of improving piezoelectric characteristics.

While the preceding working examples depicted examples using a single-crystal silicon substrate as the flow-defining substrate **10**, no particular limitation to this is imposed, and optionally, other semiconductor substrates such as Ge, transparent crystalline substrates such as SrTiO₃, InSnO₃, ZnO, Al₂O₃, or SiO₂, glass substrates, metal substrates such as stainless steel or Ti, SOI substrates, or the like may be used instead.

Further, while the preceding working examples depicted examples of piezoelectric elements **300** formed by sequential stacking of the first electrode **60**, the piezoelectric layer **70**, and the second electrodes **80** on the substrate (flow-defining substrate **10**), no particular limitation to this is imposed, and the invention may be implemented, for example, in piezoelectric elements of longitudinal oscillating type composed of alternating stacked layers of piezoelectric material and electrode-forming material that expand and contract in the axial direction.

The inkjet recording heads of these working examples constitute part of a recording head unit provided with ink channels that communicate with an ink cartridge or the like, and are installed in an inkjet recording device. FIG. 17 is a schematic diagram showing an example of such an inkjet recording device.

In the inkjet recording device II shown in FIG. 17, cartridges **2A** and **2B** are detachably installed in recording head units **1A** and **1B** provided as ink supply means and furnished with the inkjet recording head I. A carriage **3** on which these recording head units **1A** and **1B** are mounted is movably disposed in the axial direction on a carriage rail **5** that is attached to a device chassis **4**. The recording head units **1A** and **1B** respectively eject a black ink composition and color ink compositions, for example.

The carriage **3** on which the recording head units **1A** and **1B** are mounted travels along the carriage rail **5** through transmission of drive power from a drive motor **6** to the carriage **3** via a number of gears, not shown, and a timing belt **7**. The device chassis **4** has a platen **8** which is disposed along the carriage rail **5**, and a recording sheet **S** of a recording medium such as paper which is supplied by feed rollers, not shown, or the like is advanced while wound around the platen **8**.

While the preceding first working example described an inkjet recording head by way of an example of a liquid ejection head, the present invention is directed generally to all manner of liquid ejection devices, and, as shall be apparent, may be implemented in liquid ejection heads that eject liquids other than ink. Examples of other liquid ejection heads are recording heads of various kinds used in image recording devices such as printers; color material ejection heads used in the manufacture of color filters for liquid crystal displays and the like; electrode material ejection heads used for electrode formation in organic EL displays, field emission displays (FED), and the like; and bioorganic compound ejection heads used in the manufacture of biochips.

The present invention is not limited to piezoelectric elements mounted on liquid ejection heads typified by inkjet recording heads, and may be implemented analogously in

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piezoelectric elements for ultrasound transmitters and other ultrasound devices, ultrasound motors, or infrared sensors, ultrasound sensors, heat sensitive sensors, pressure sensors, pyroelectric sensors, acceleration sensors, gyro sensors, and various other types of sensors. Further, the present invention may be implemented analogously in ferroelectric elements such as ferroelectric memory, or in micro liquid pumps, thin ceramic capacitors, gate insulating films, and the like.

GENERAL INTERPRETATION OF TERMS

In understanding the scope of the present invention, the term “comprising” and its derivatives, as used herein, are intended to be open ended terms that specify the presence of the stated features, elements, components, groups, integers, and/or steps, but do not exclude the presence of other unstated features, elements, components, groups, integers and/or steps. The foregoing also applies to words having similar meanings such as the terms, “including”, “having” and their derivatives. Also, the terms “part,” “section,” “portion,” “member” or “element” when used in the singular can have the dual meaning of a single part or a plurality of parts. Finally, terms of degree such as “substantially”, “about” and “approximately” as used herein mean a reasonable amount of deviation of the modified term such that the end result is not significantly changed. For example, these terms can be construed as including a deviation of at least $\pm 5\%$ of the modified term if this deviation would not negate the meaning of the word it modifies.

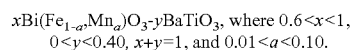
While only selected embodiments have been chosen to illustrate the present invention, it will be apparent to those skilled in the art from this disclosure that various changes and modifications can be made herein without departing from the scope of the invention as defined in the appended claims.

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Furthermore, the foregoing descriptions of the embodiments according to the present invention are provided for illustration only, and not for the purpose of limiting the invention as defined by the appended claims and their equivalents.

What is claimed is:

1. A piezoelectric element comprising:
 - a piezoelectric layer; and
 - an electrode provided on the piezoelectric layer, the electrode being oriented with the (111) plane, wherein the piezoelectric layer is made of a piezoelectric material containing a perovskite compound that includes at least bismuth manganate ferrate and barium titanate, the piezoelectric layer is preferentially oriented with the (110) plane, with a degree of orientation of the (110) plane being 60% or more, and
 - a full width at half maximum of the X-ray diffraction peak attributed to the (110) plane is 0.24° or more and 0.28° or less,
- the piezoelectric layer including silicon dioxide in an amount of 0.5 mol % or more and 5 mol % or less with respect to the perovskite compound.
2. A liquid ejection head comprising the piezoelectric element according to claim 1.
3. A liquid ejection device comprising the liquid ejection head according to claim 2.
4. The piezoelectric element according to claim 1, wherein the piezoelectric layer is made of a piezoelectric material including at least bismuth manganate ferrate and barium titanate, as defined by:



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